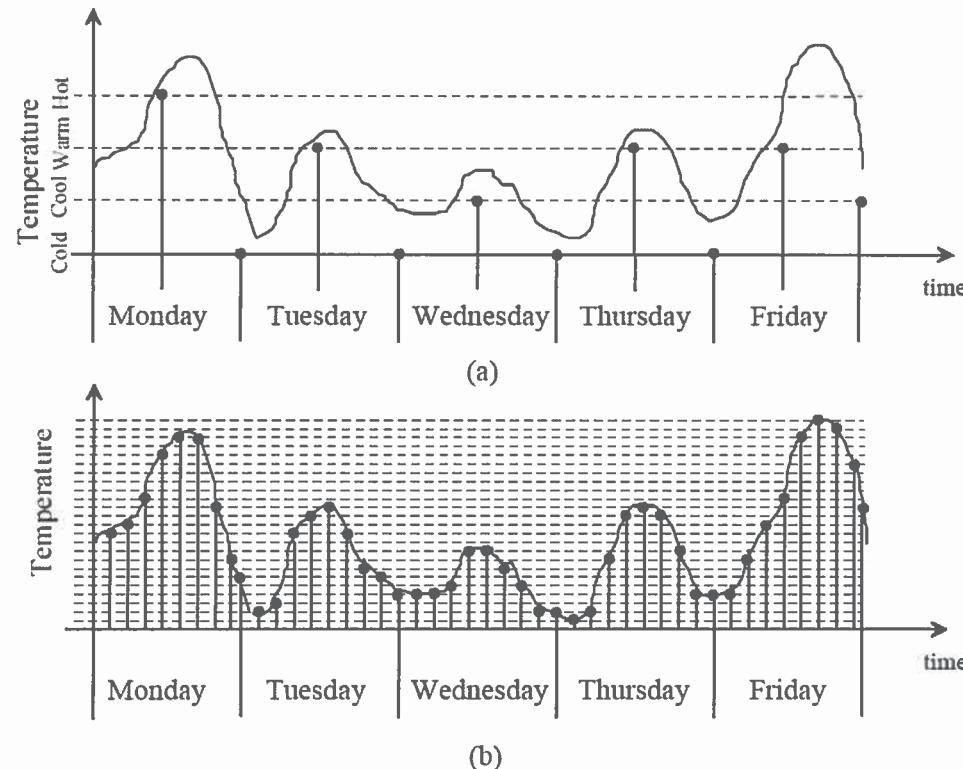
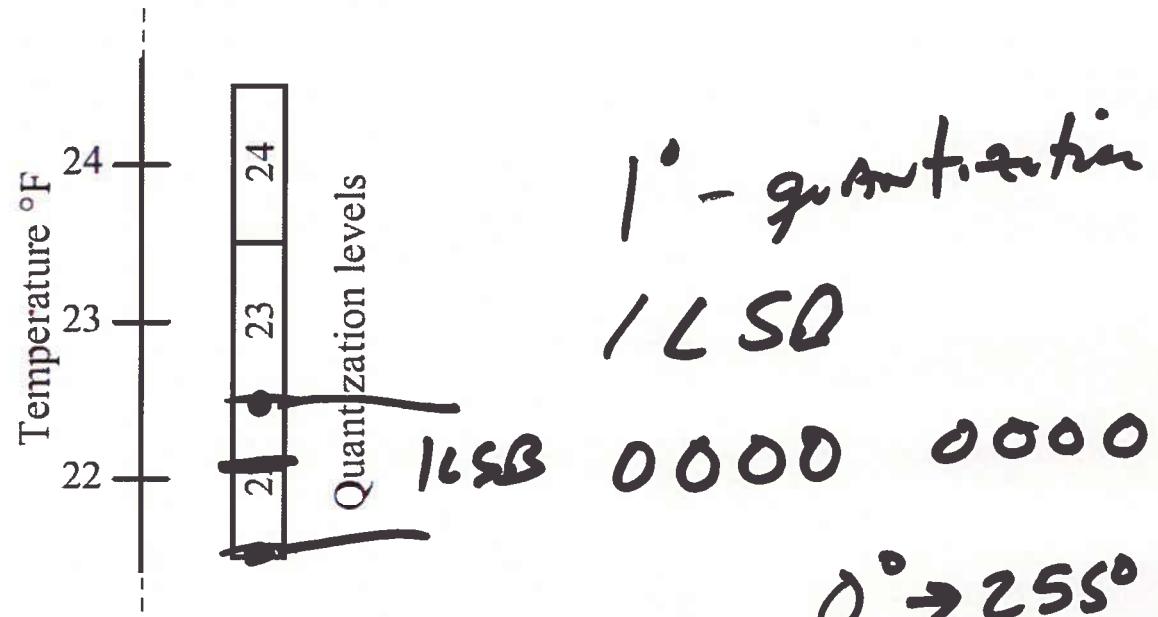


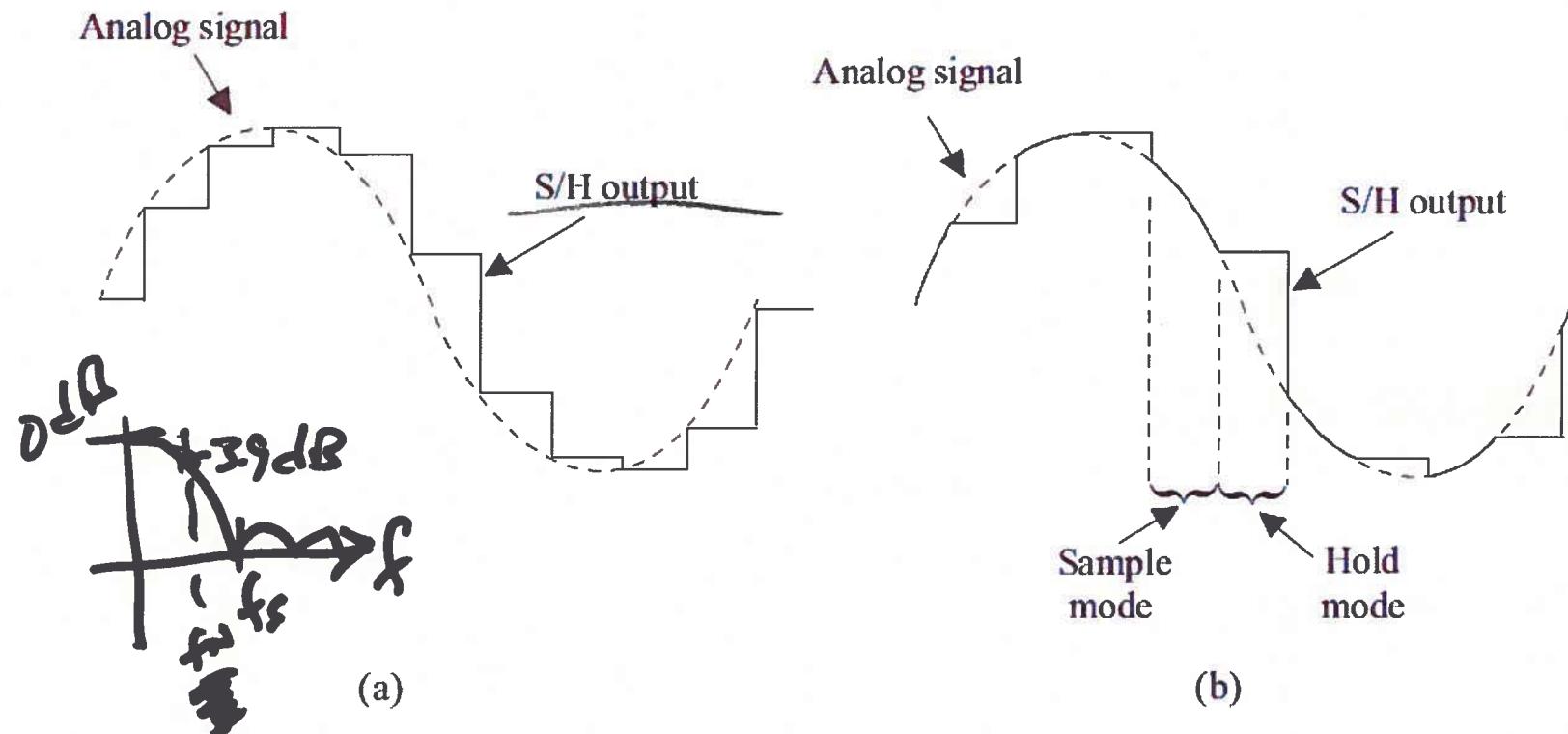
**Figure 28.2** (a) An analog signal representing the temperature where you live and  
(b) a digital representation of the analog signal taking one sample per day with two quantization levels.



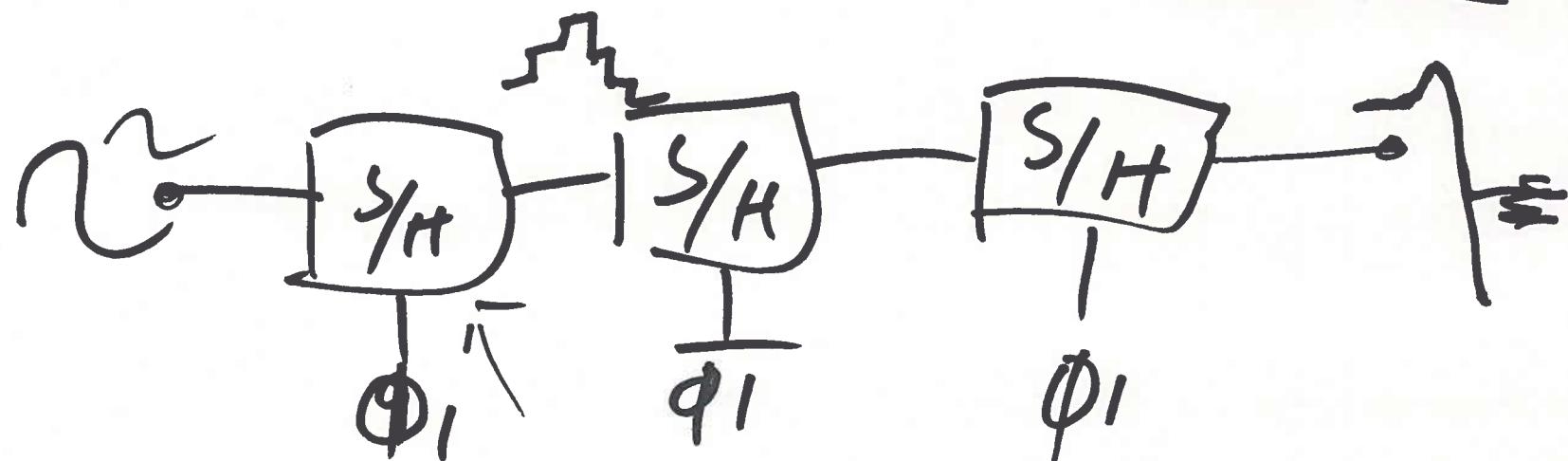
**Figure 28.3** Digital representation of the temperature taking (a) two samples per day with four quantization levels and (b) nine samples per day with 25 quantization levels.



**Figure 28.4** Quantization levels overlap actual temperature by  $\pm\frac{1}{2}^{\circ}$  F.



**Figure 28.5** The output of (a) an ideal S/H circuit and (b) a track-and-hold (T/H).



Figures from CMOS Circuit Design, Layout, and Simulation, Copyright Wiley-IEEE, CMOSedu.com

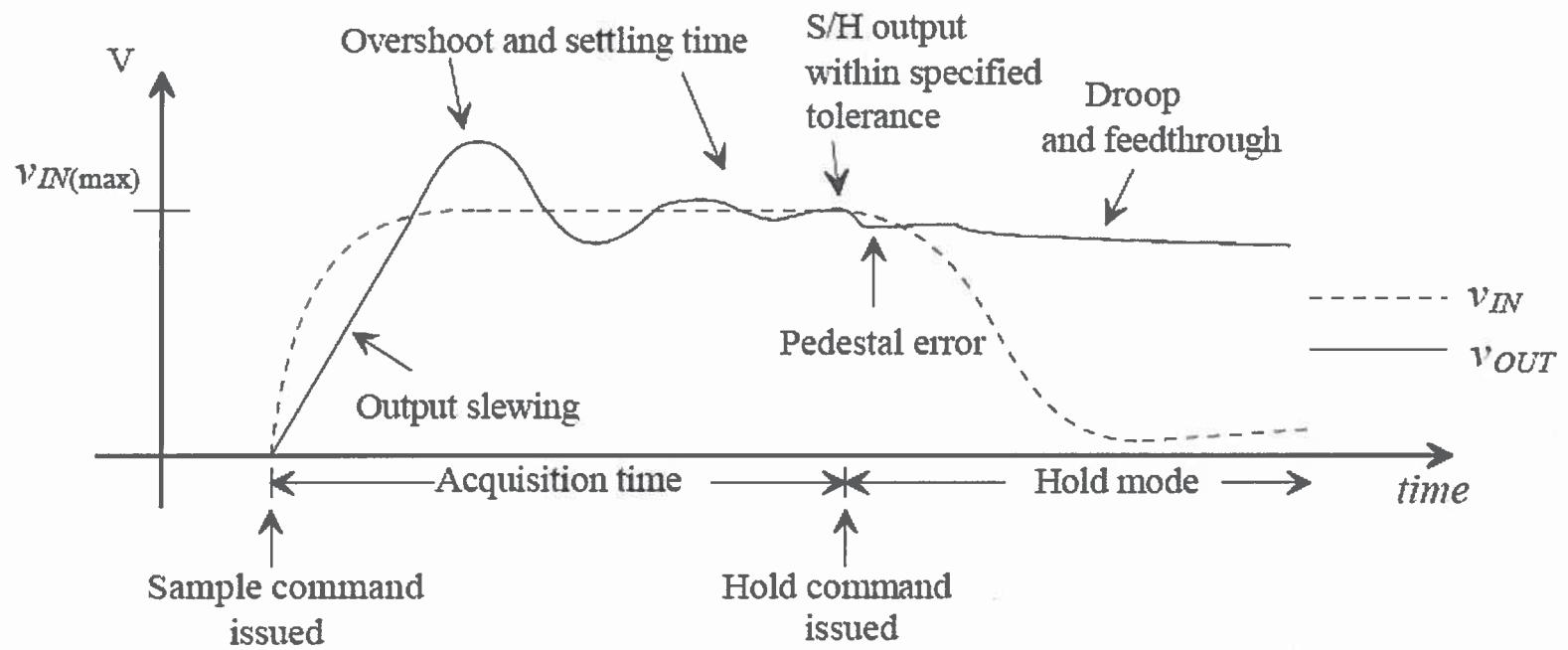


Figure 28.6 Typical errors associated wth an S/H.

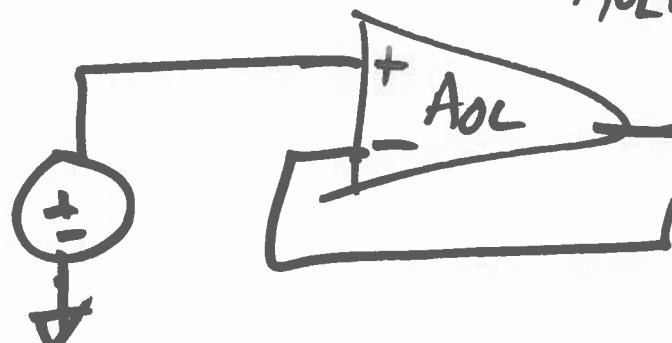
$$V_o = A_{OL} (1 - V_o)$$

$1 \mu V$

$$V_o (1 + A_{OL}) = A_{OL}$$

$1 \mu V$

$$V_o = \frac{A_{OL}}{1 + A_{OL}}$$



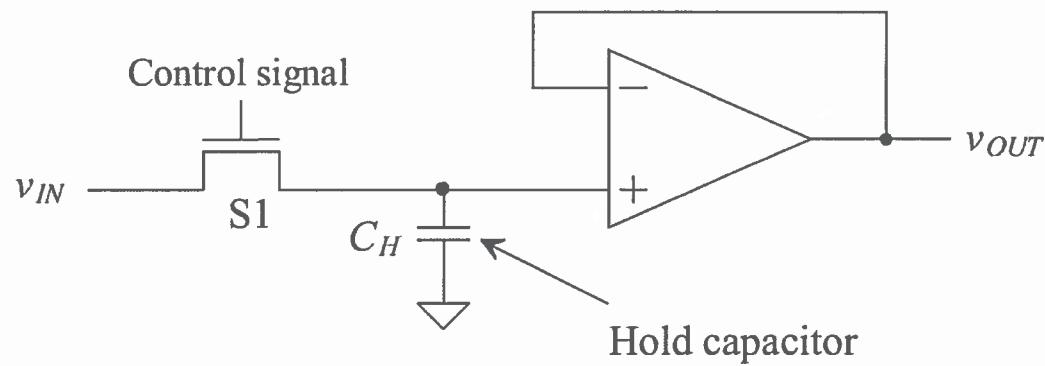
$$A_{OL} M.V = ?$$

$A_{OL_{min.}} \gg 1,000$

$$V_o \approx 1 V$$

$$V_o \ggg .999 V$$

$$V_o < 1 V$$



**Figure 28.7** Track-and-hold circuit using an output buffer.

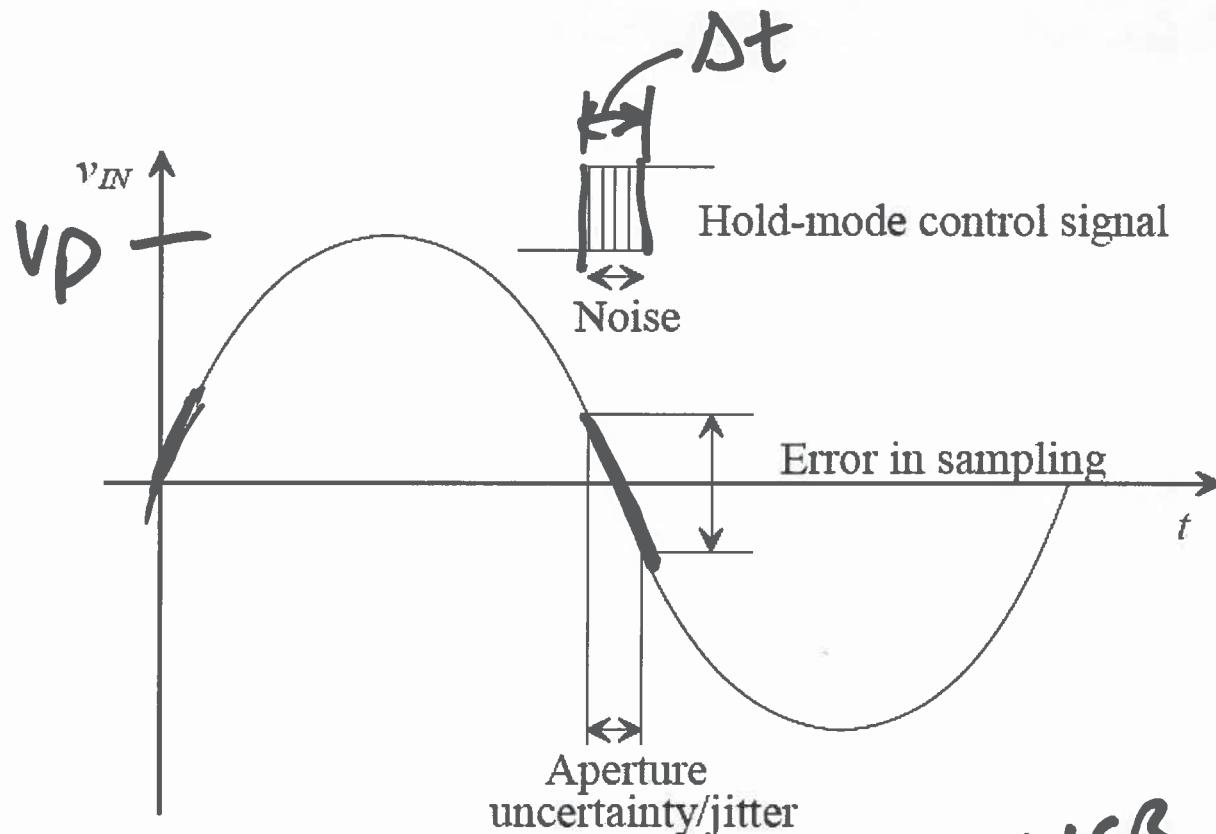
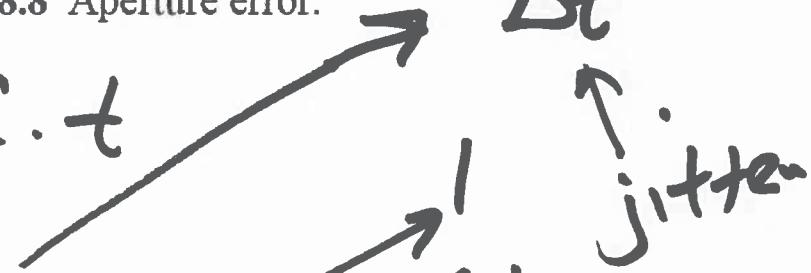


Figure 28.8 Aperture error.

$$\frac{1 \text{ LSB}}{\Delta t} = V_p \cdot 2\pi f$$

$$v_{in} = V_p \cdot \sin 2\pi f \cdot t$$



$$\frac{dv_{in}}{dt} = V_p \cdot 2\pi f \cdot \cos 2\pi f t$$

8)

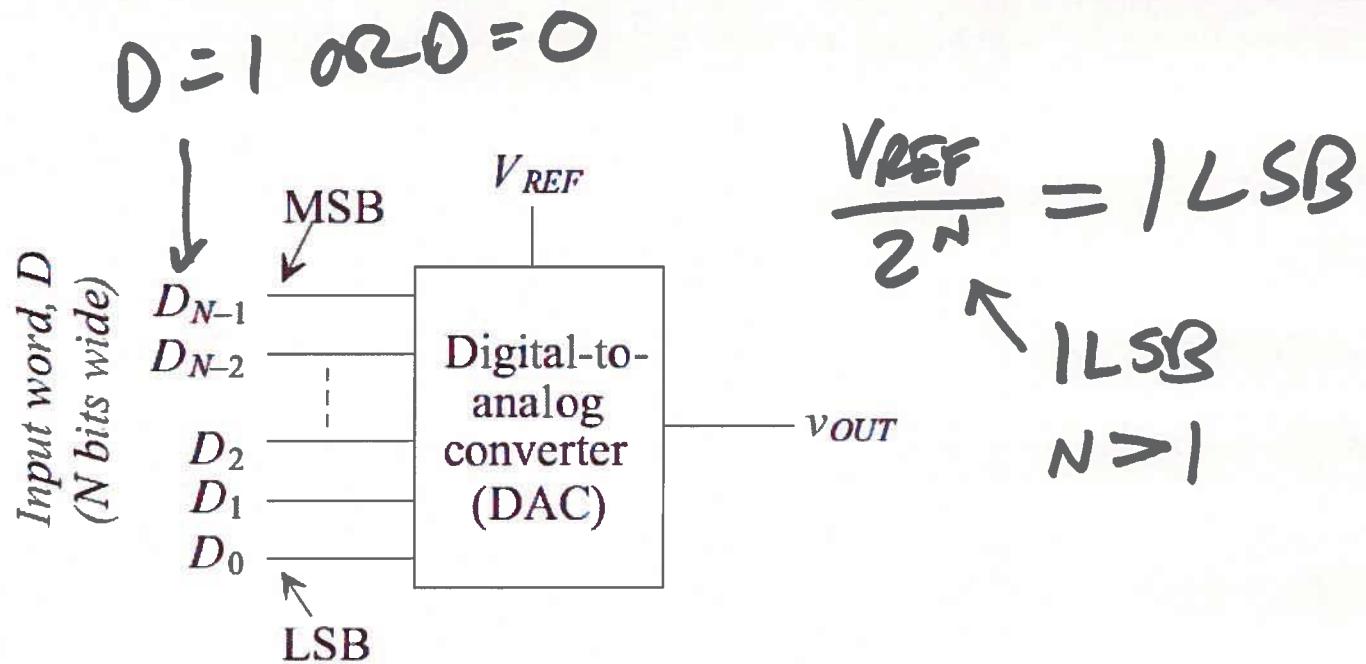


Figure 28.9 Block diagram of the digital-to-analog converter.

$$V_{OUT} = \frac{V_{REF}}{2^N} \cdot \left( \frac{D_0}{2^0} + \frac{3D_1}{2^{0+1}} + \frac{4D_2}{2^{0+2}} + 2^3 \cdot D_3 + \dots + \frac{2^{N-2}D_{N-2}}{2^{N-2}} + \frac{2^{N-1} \cdot D_{N-1}}{2^N} \right)$$

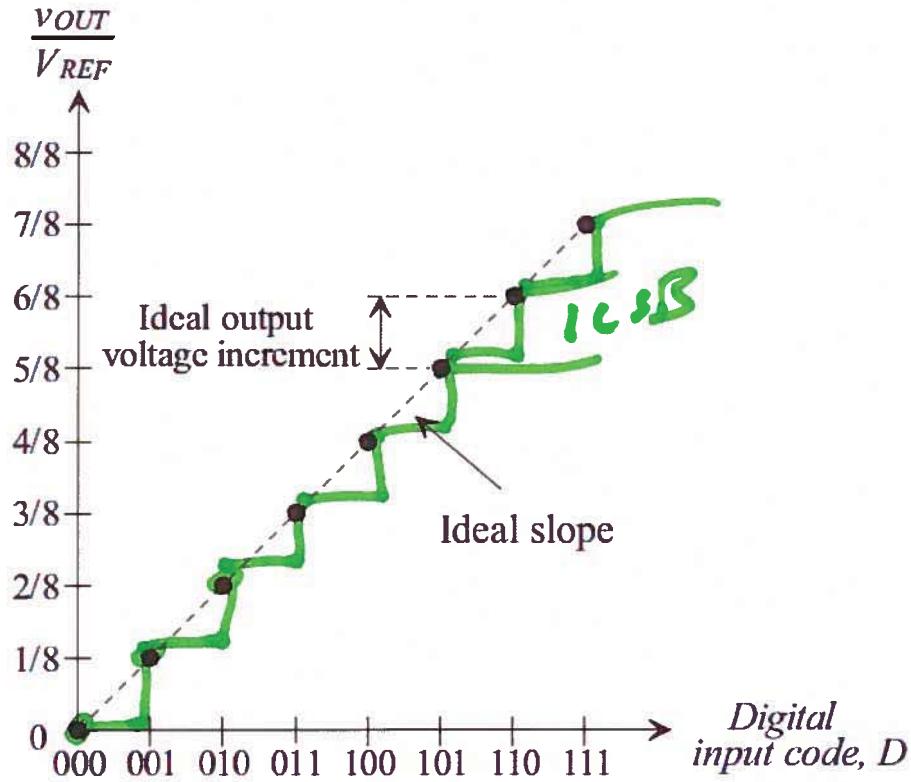


Figure 28.10 Ideal transfer curve for a 3-bit DAC.

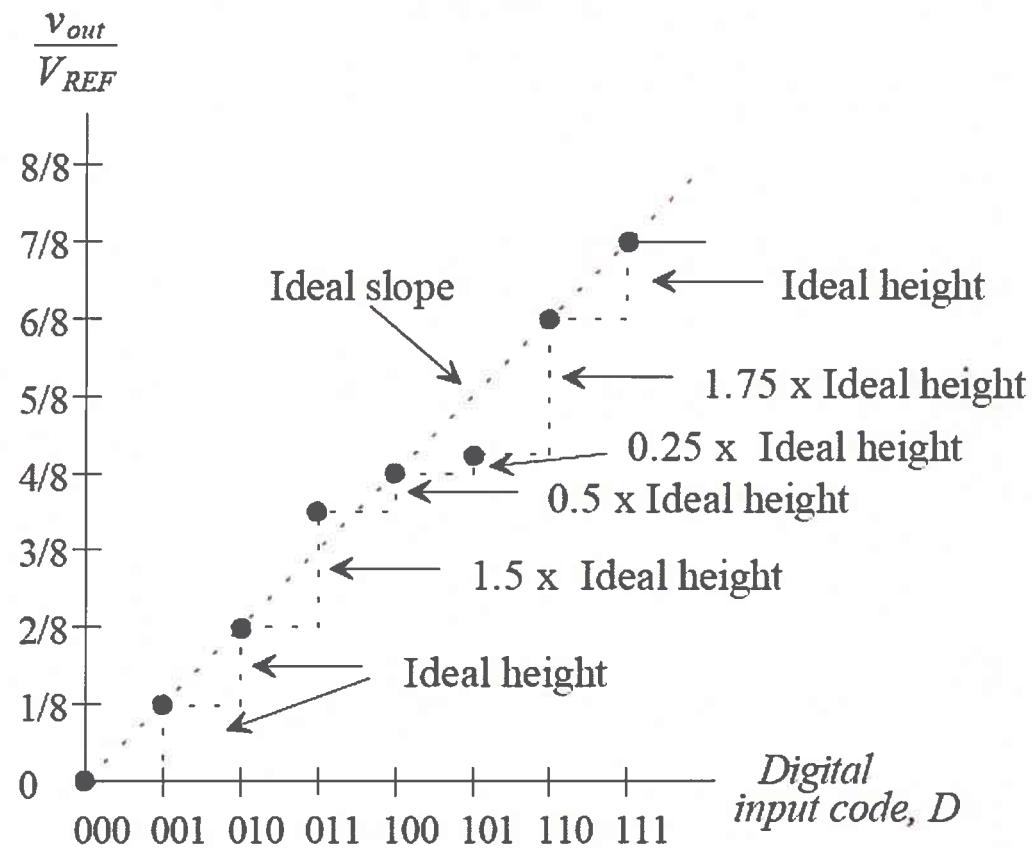


Figure 28.11 Example of differential nonlinearity for a 3-bit DAC.



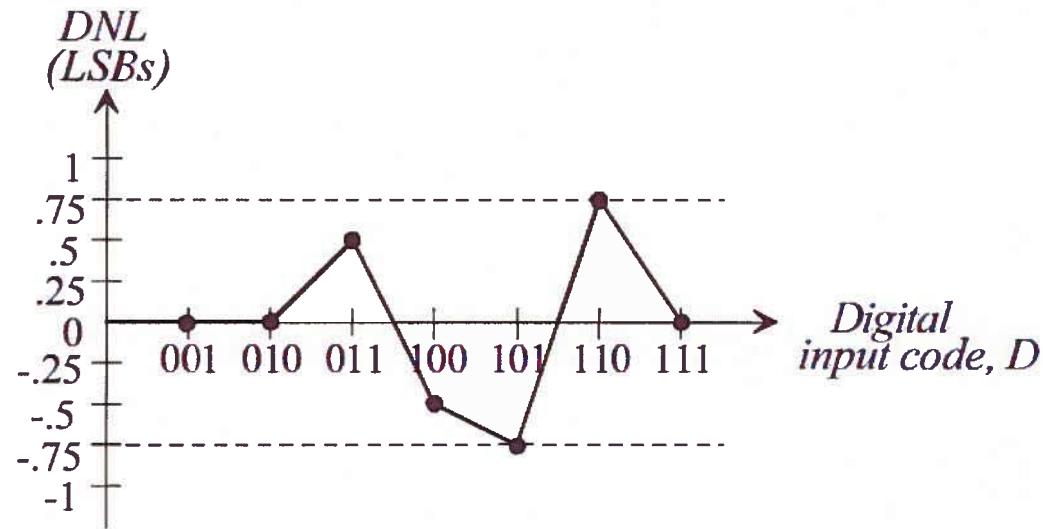
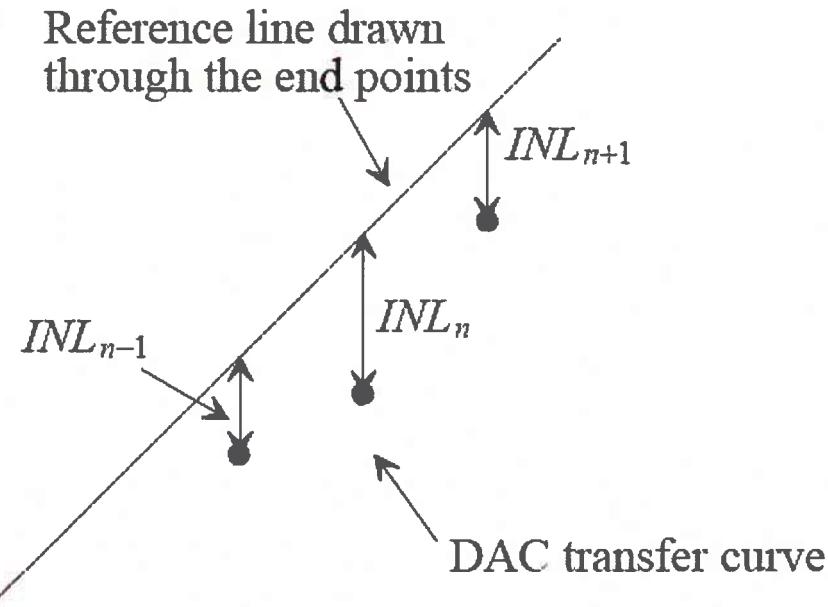
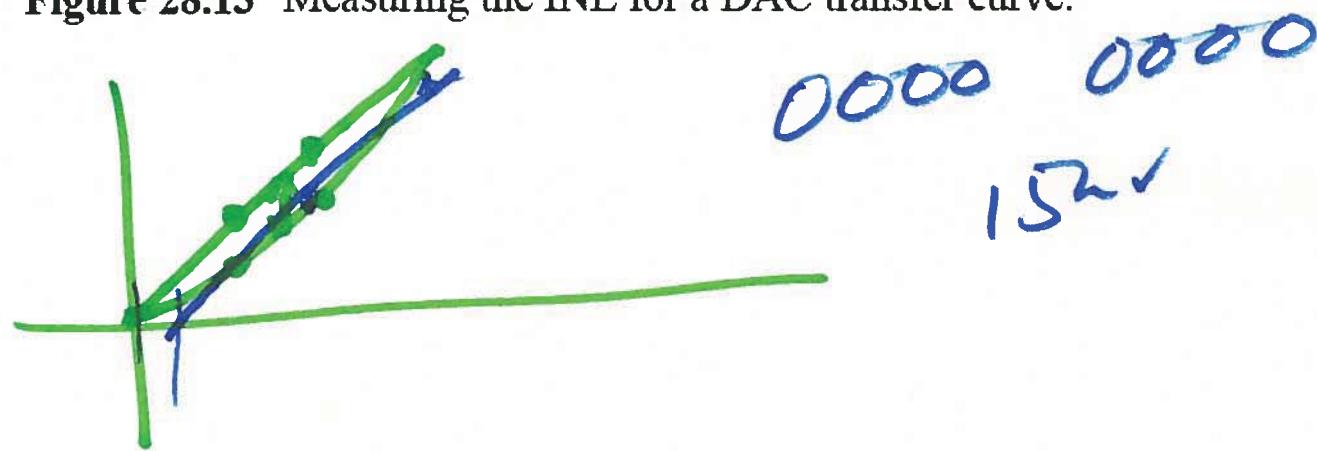


Figure 28.12 DNL curve for the nonideal 3-bit DAC.

$$|DNL| < \frac{1}{2} LSB$$



**Figure 28.13** Measuring the INL for a DAC transfer curve.



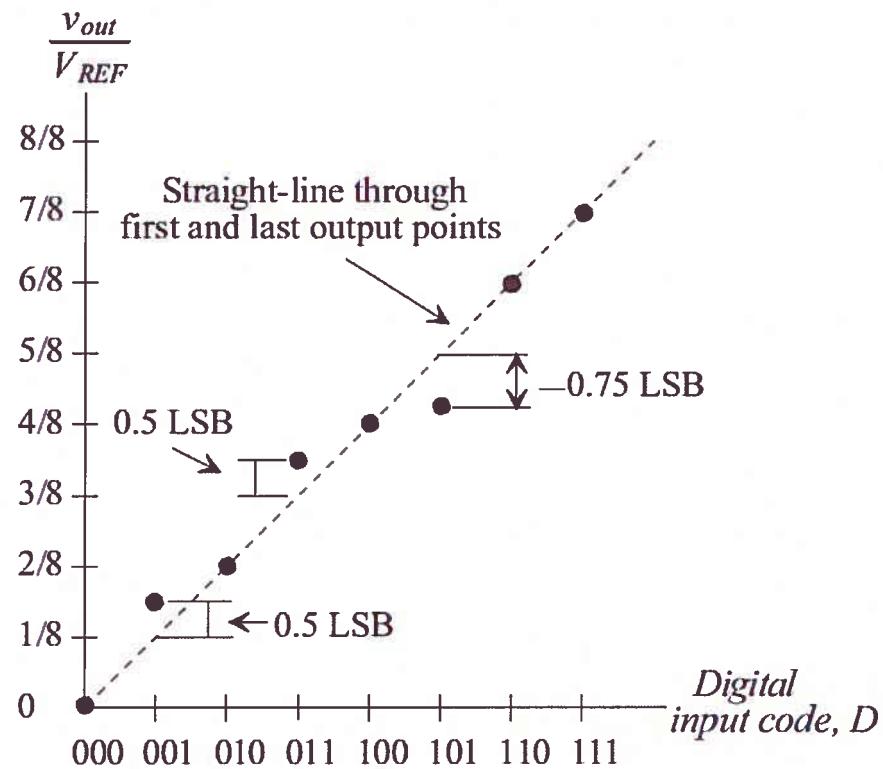


Figure 28.14 Example of integral nonlinearity for a DAC.

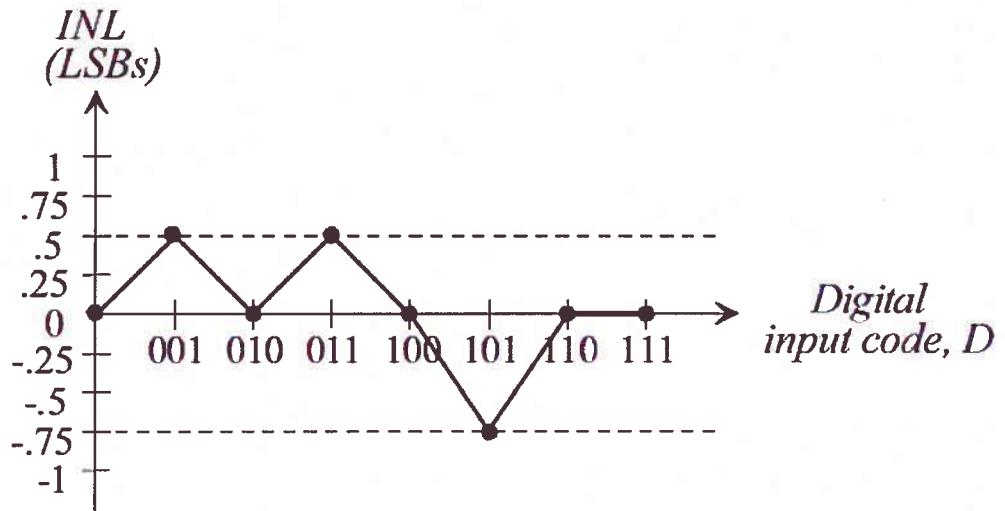
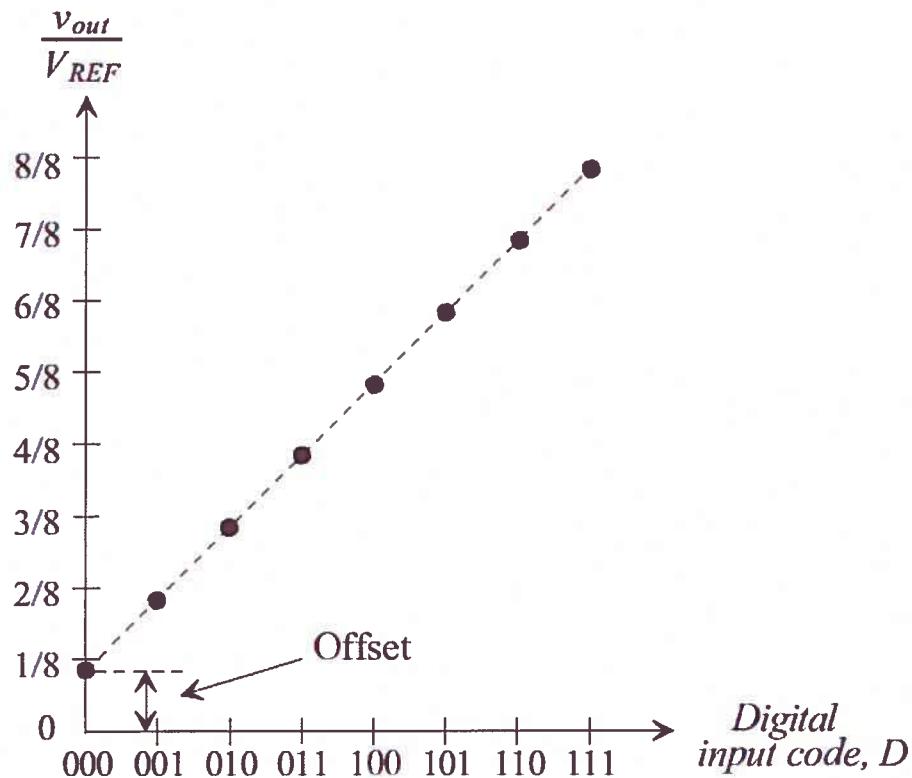


Figure 28.15 INL curve for the nonideal 3-bit DAC.

Integral Nonlinearity

INL



**Figure 28.16** Illustration of offset error for a 3-bit DAC.

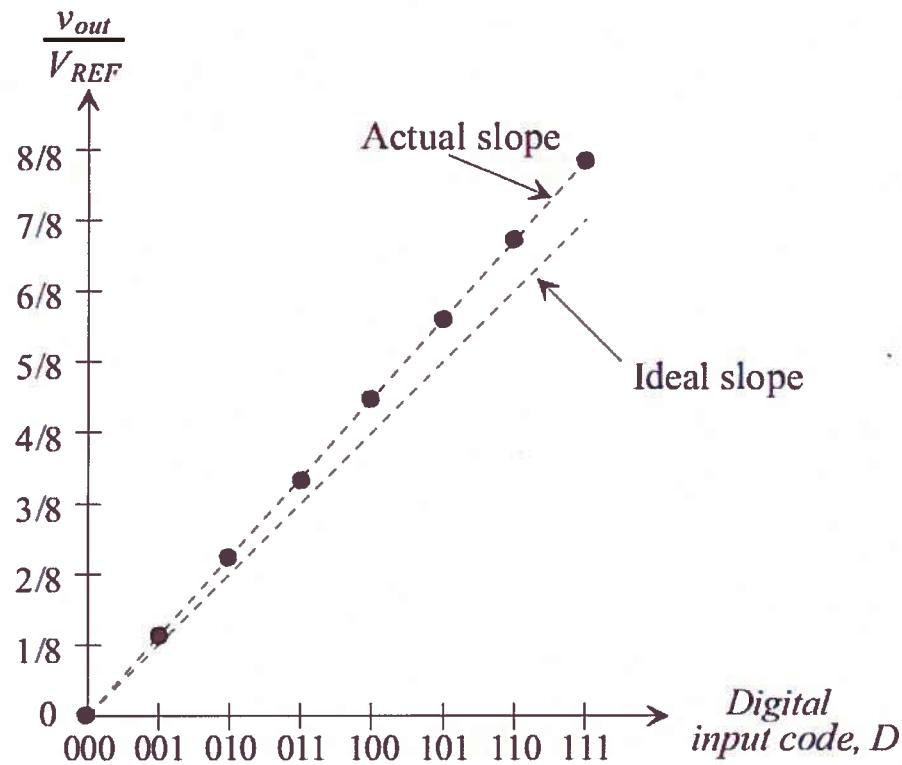
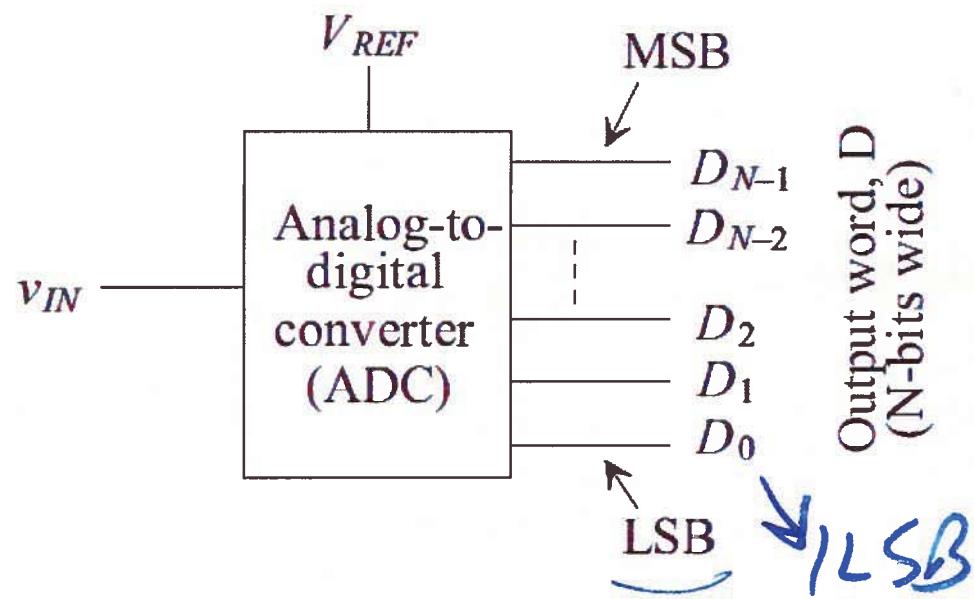
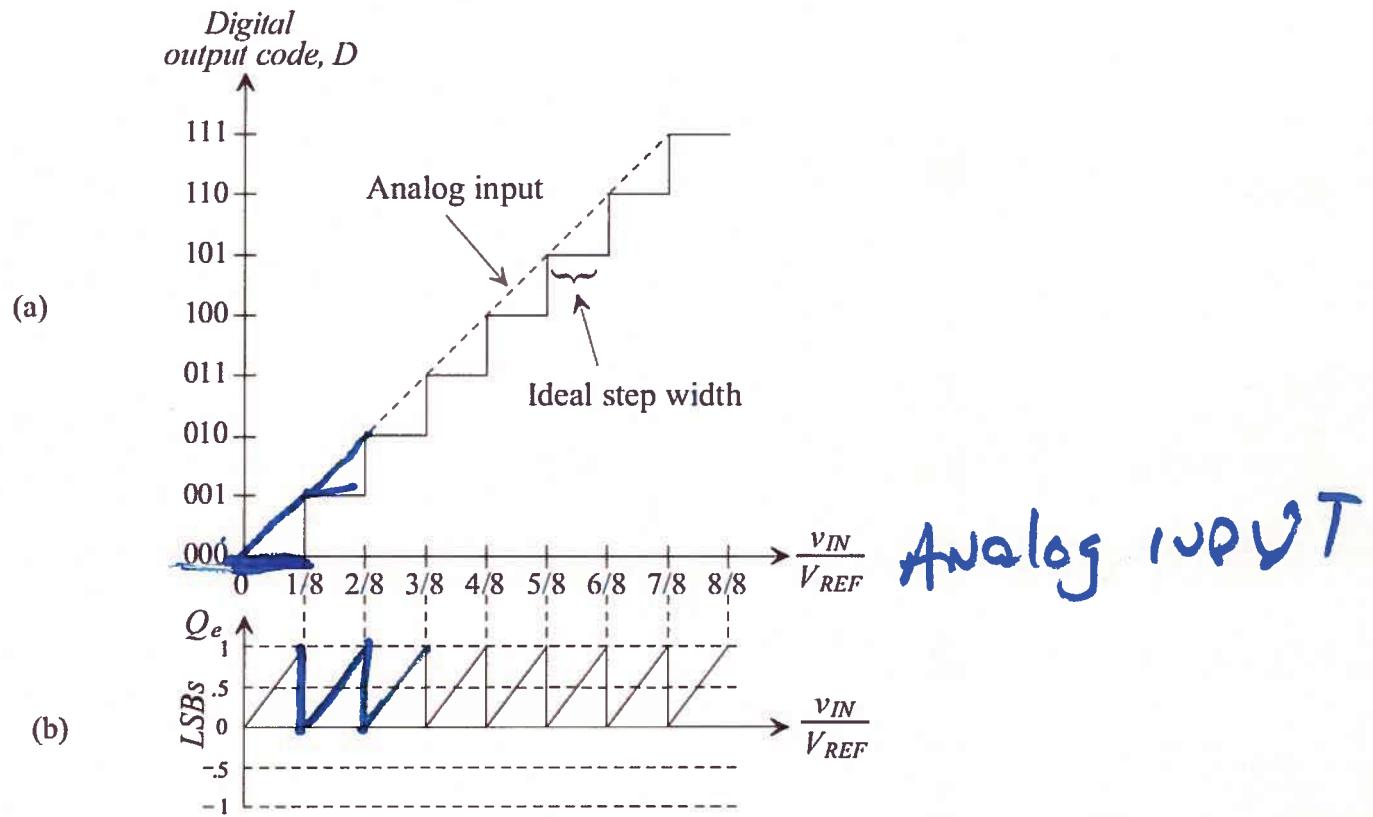


Figure 28.17 Illustration of gain error for a 3-bit DAC.



**Figure 28.18** Block diagram of the analog-to-digital converter.



**Figure 28.19** (a) Transfer curve for an ideal ADC and (b) its corresponding quantization error.

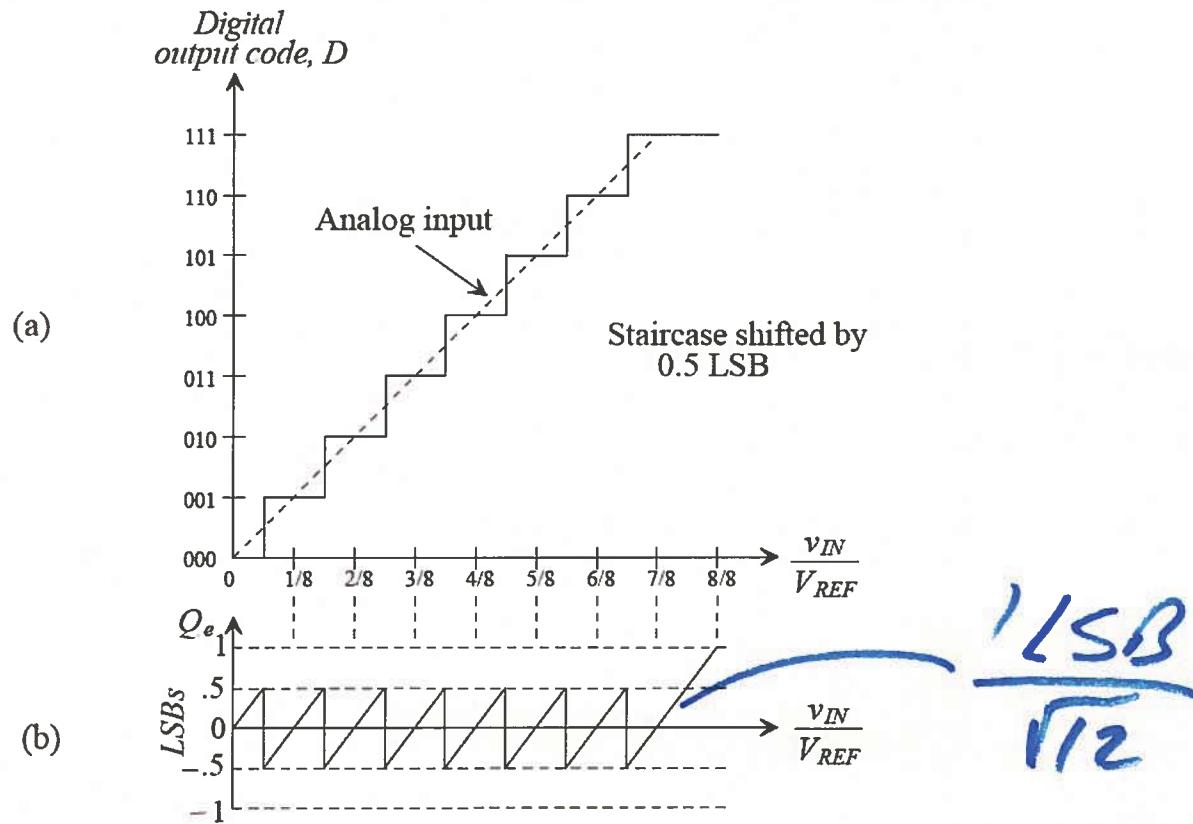
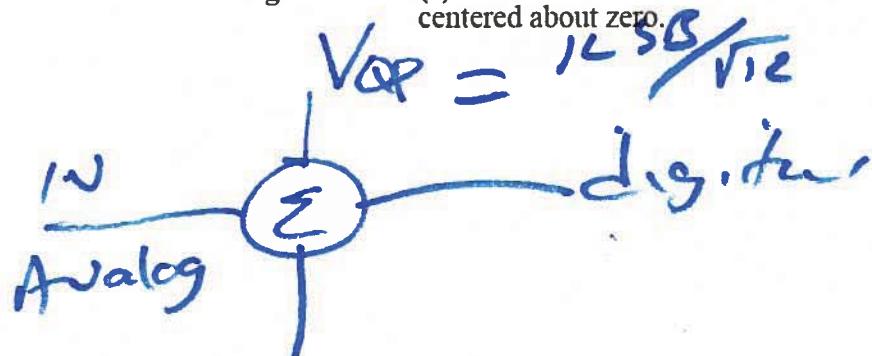
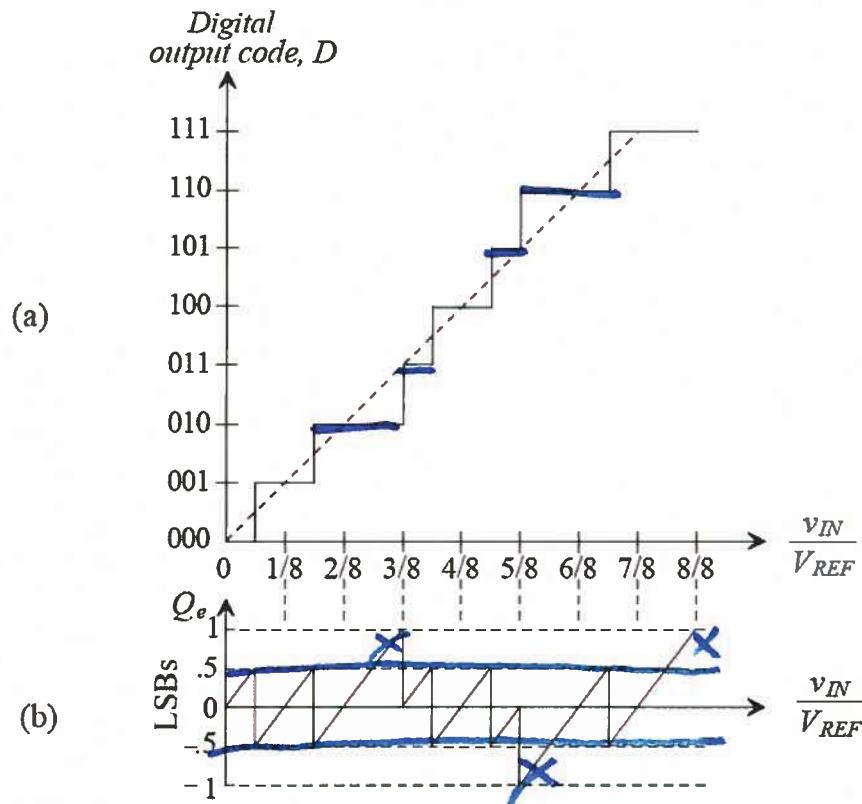
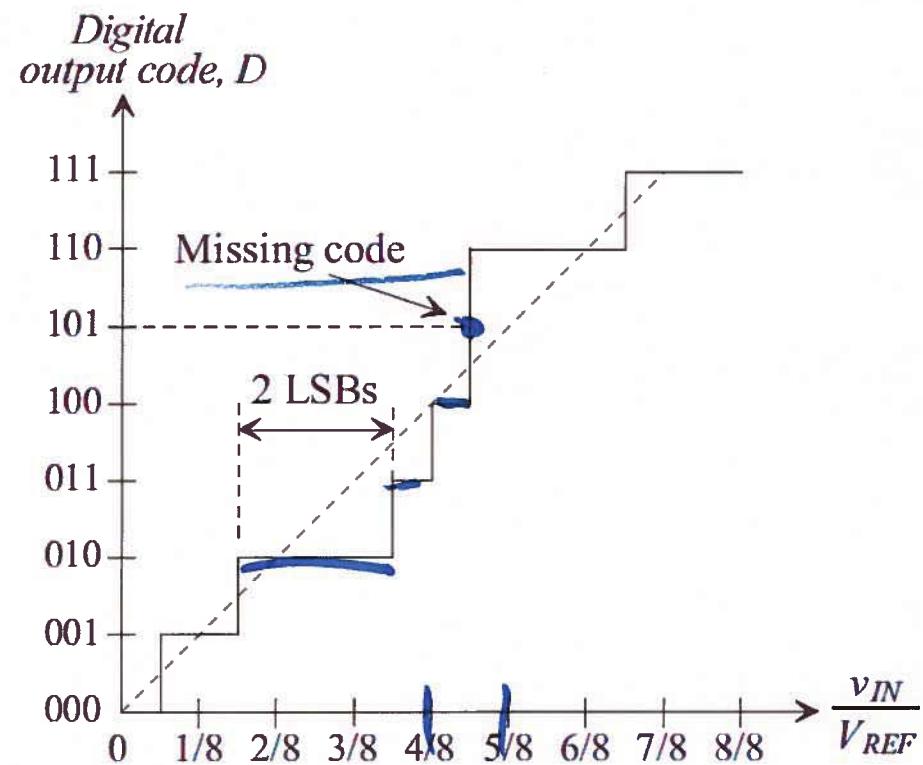


Figure 28.20 (a) Transfer curve for an ideal 3-bit ADC with (b) quantization error centered about zero.

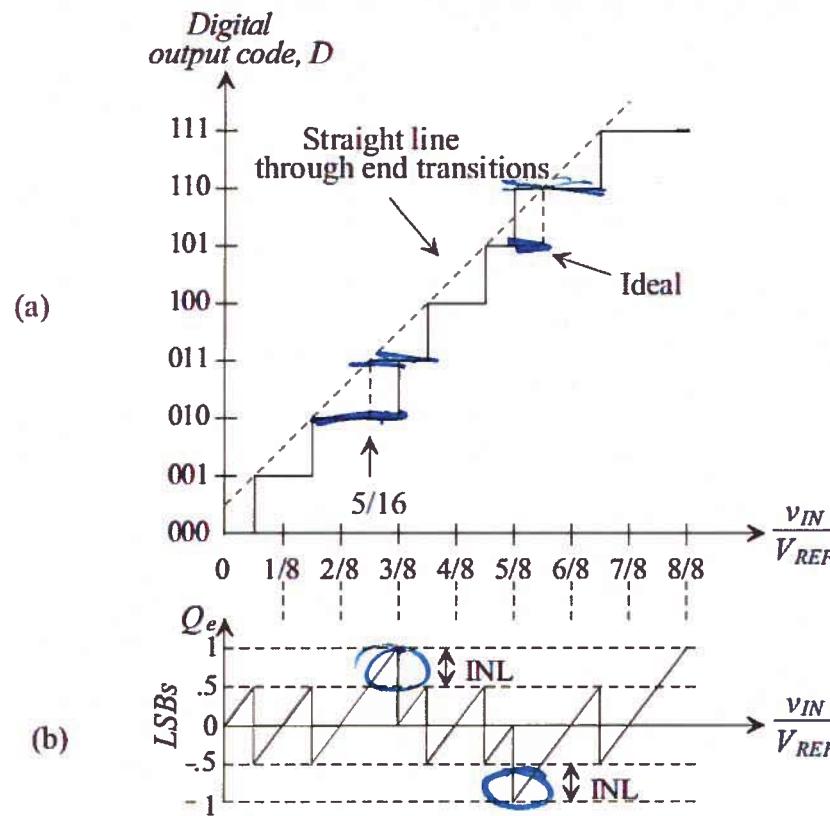




**Figure 28.21** (a) Transfer curve for a nonideal 3-bit ADC used in Ex. 28.4 with  
(b) quantization error illustrating differential nonlinearity.



**Figure 28.22** Transfer curve for a nonideal 3-bit ADC with a missing code.



**Figure 28.23** (a) Transfer curve of a nonideal 3-bit ADC and (b) its quantization error illustrating INL.

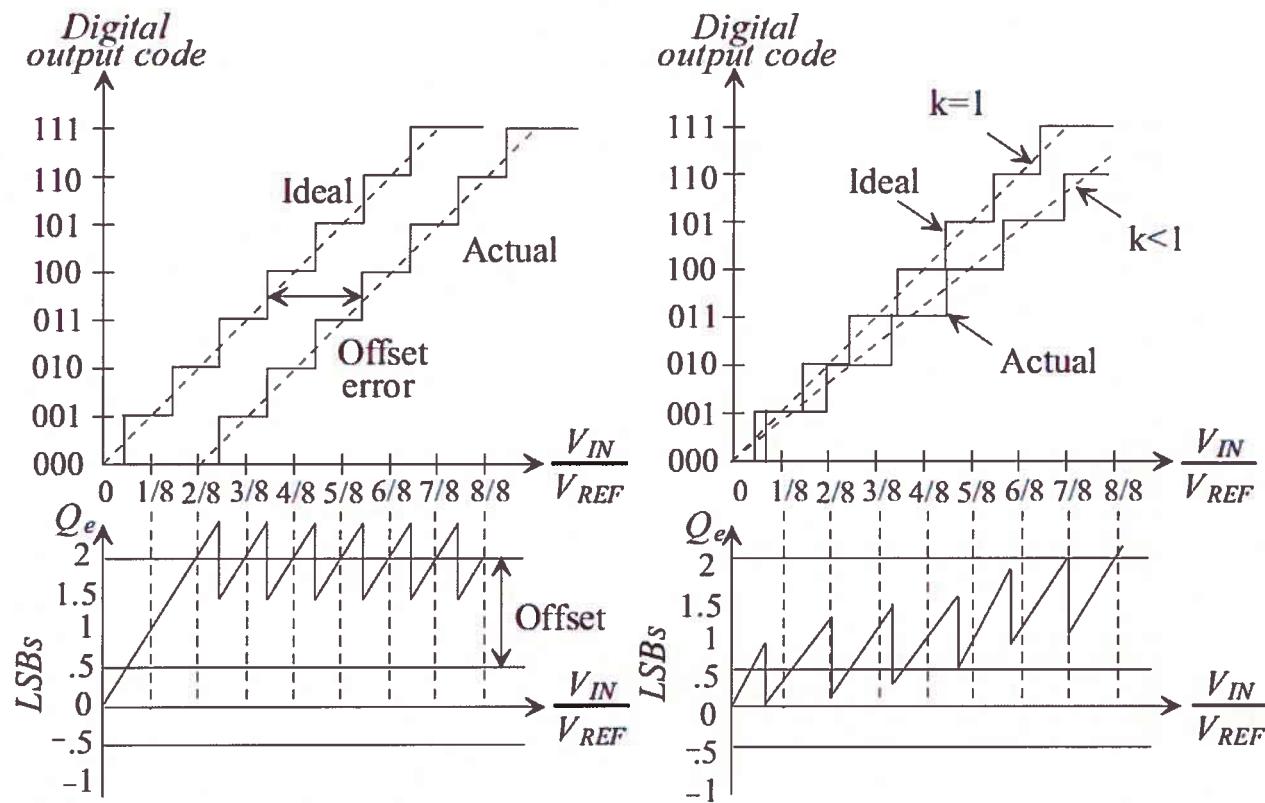
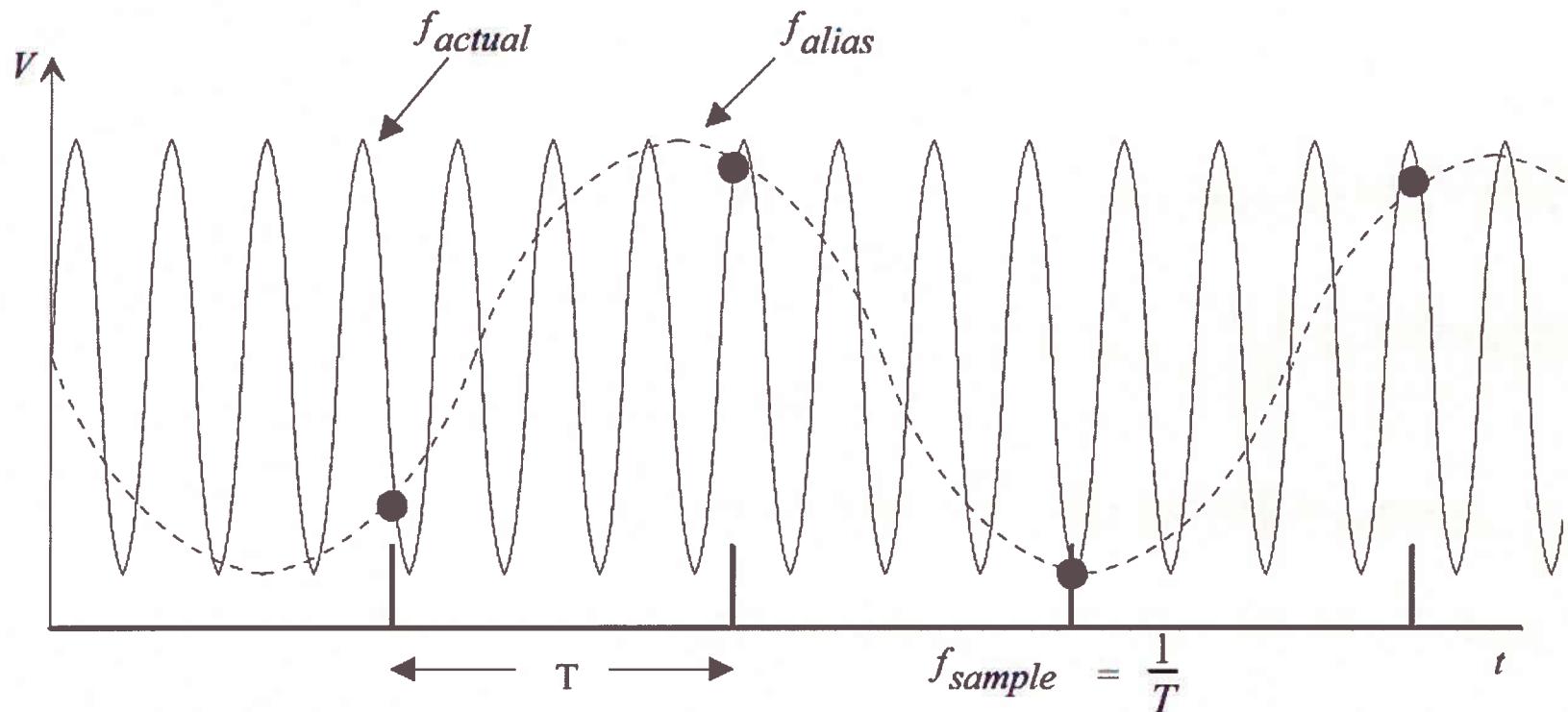


Figure 28.24 Transfer curve illustrating (a) offset error and (b) gain error.



**Figure 28.25** Aliasing caused by undersampling.

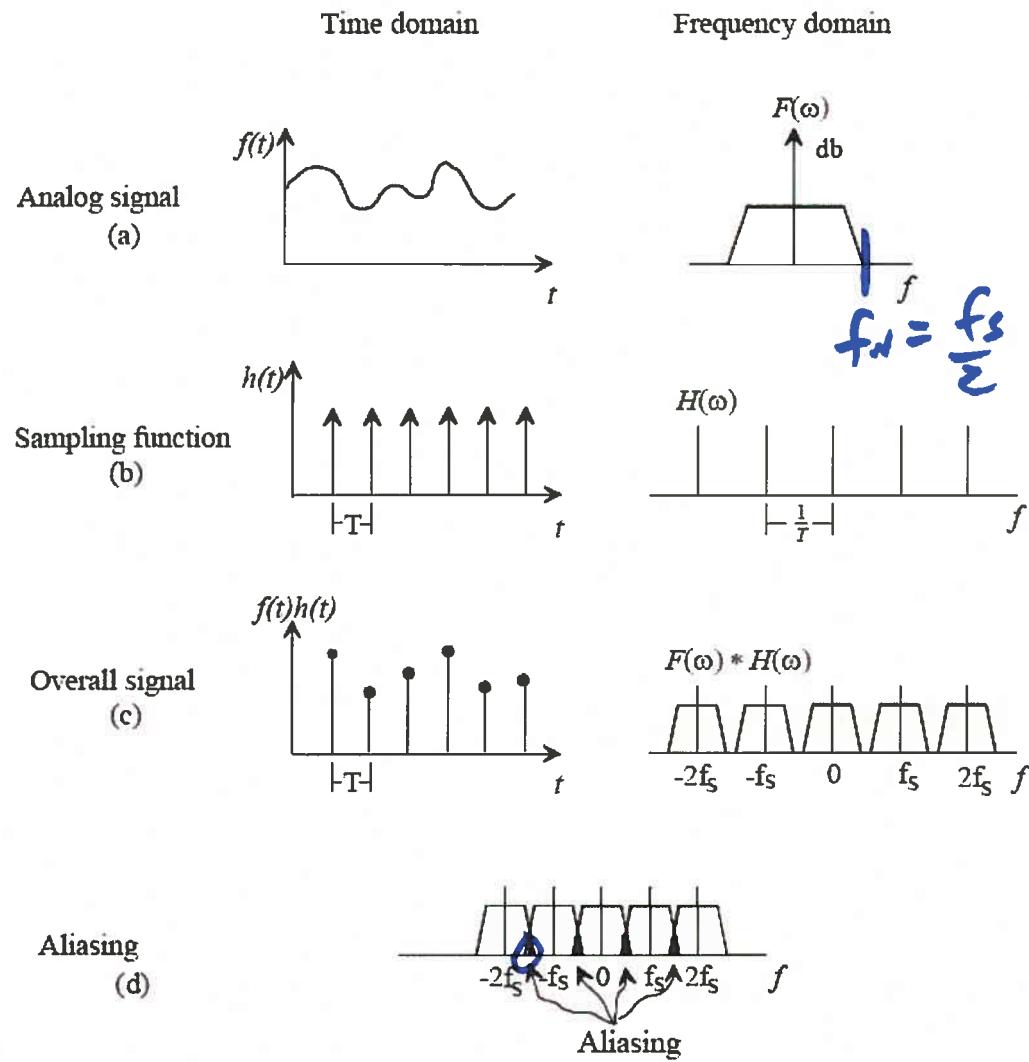


Figure 28.26 Illustration of aliasing in the time and frequency domain. (a) The analog signal; (b) the sampling function; (c) the overall signal; and (d) aliasing in the frequency domain.

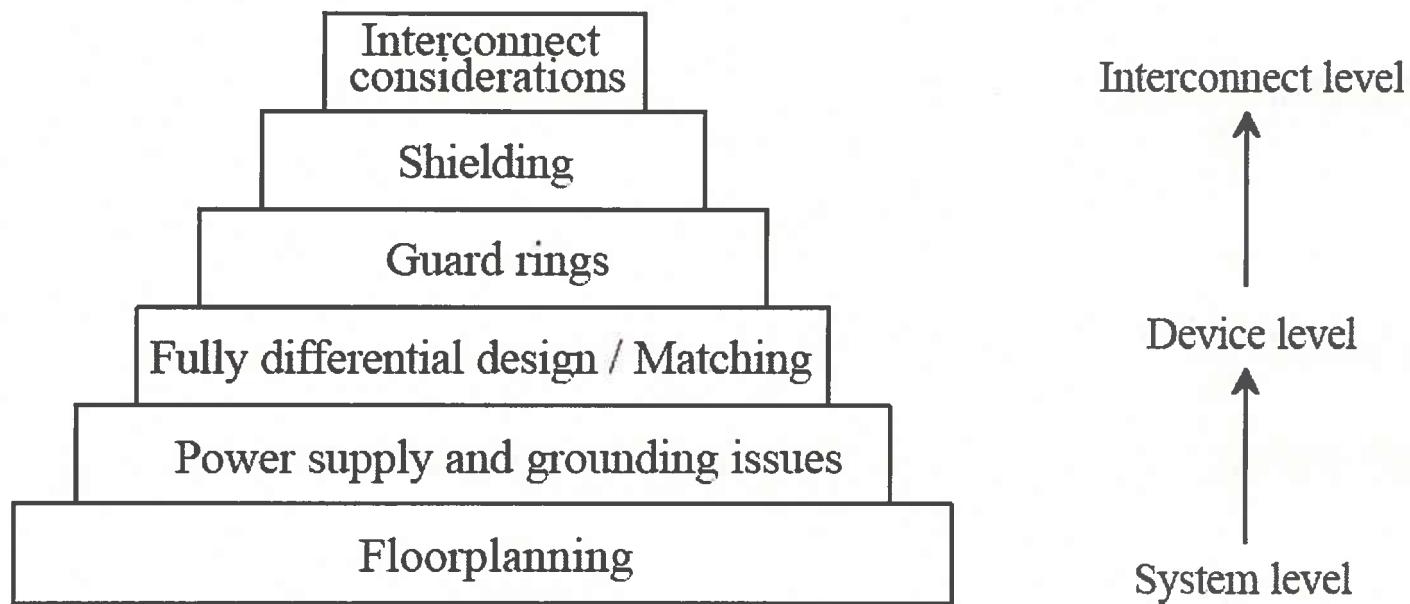
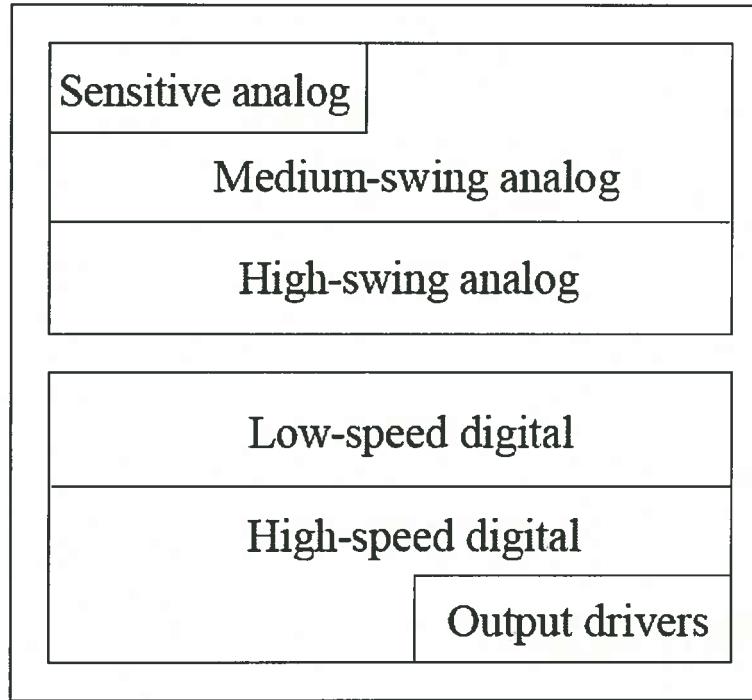


Figure 28.27 Mixed-signal layout strategy.

27)  
Analog



**Figure 28.28** Example of a mixed-signal floorplan [1].

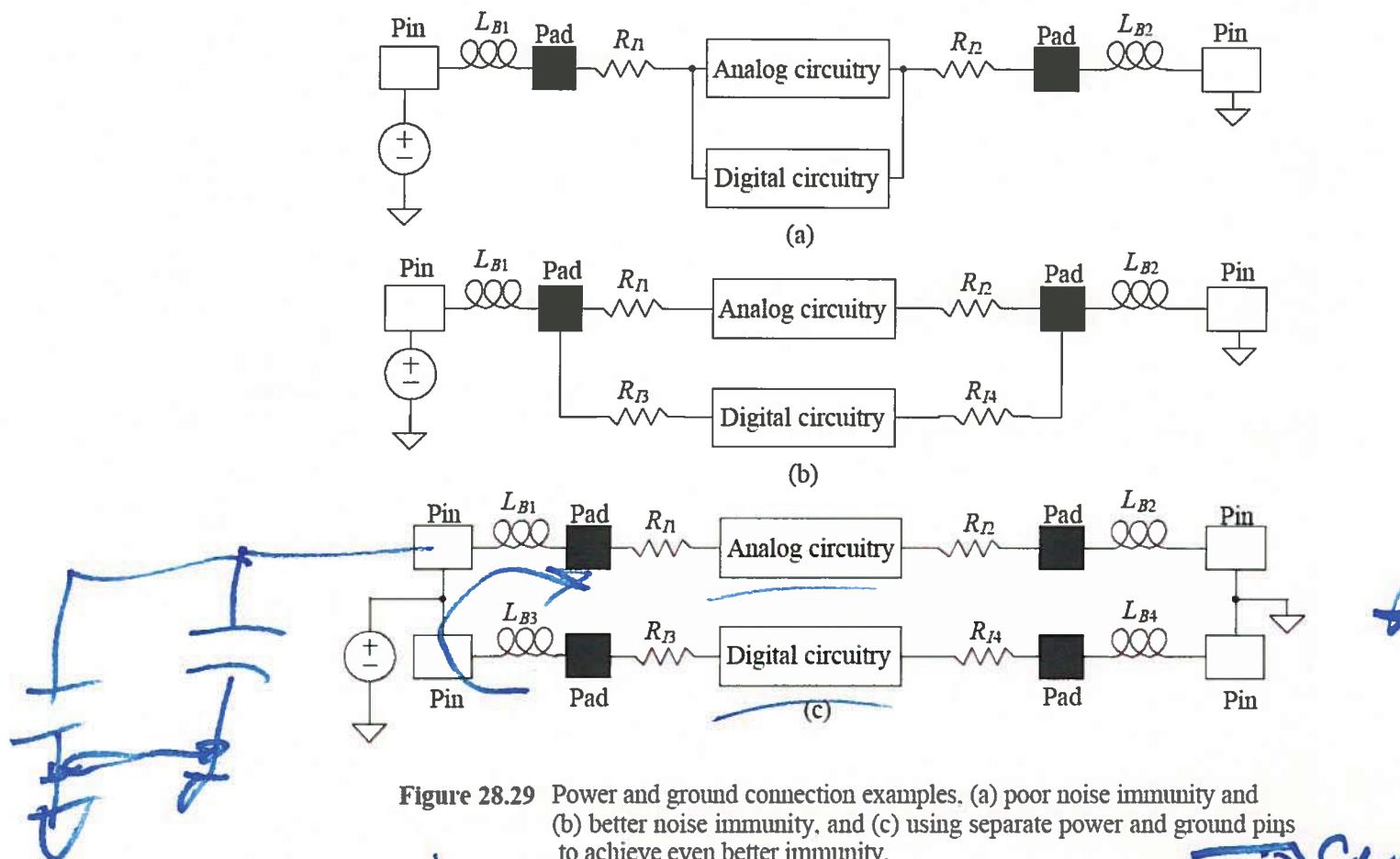


Figure 28.29 Power and ground connection examples. (a) poor noise immunity and (b) better noise immunity, and (c) using separate power and ground pins to achieve even better immunity.